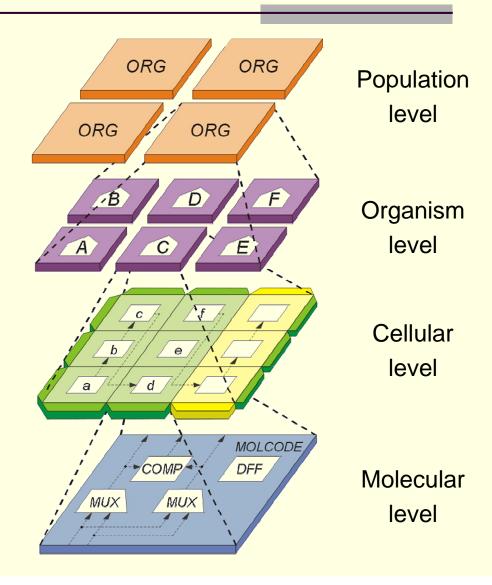
Self-Repairing Embryonic Memory Arrays

Lucian Prodan Mihai Udrescu Mircea Vladutiu

"Politehnica" University of Timisoara ROMANIA

What is Embryonics?

Bio-inspired computing system
Aimed at transferring biological robustness into digital electronics
Four-level system architecture hierarchy
Hierarchical self-repairing



The Genetic Program

Cells delimited by polymerase genome (the cellular membrane or space divider)

Molecules configured by ribosomic genome

Two operating modes possible for a molecule

Logic mode: a functional unit based on two multiplexers and a flip-flop, together with signal routing mechanism to and from neighbors

Memory mode: program called **operative genome**

The Memory Mode

Genetic program stored by each molecule in pieces of either 8 bits or 16 bits

Memory structures are made of molecules, are delimited by a membrane mechanism, but are not cells macro-molecules

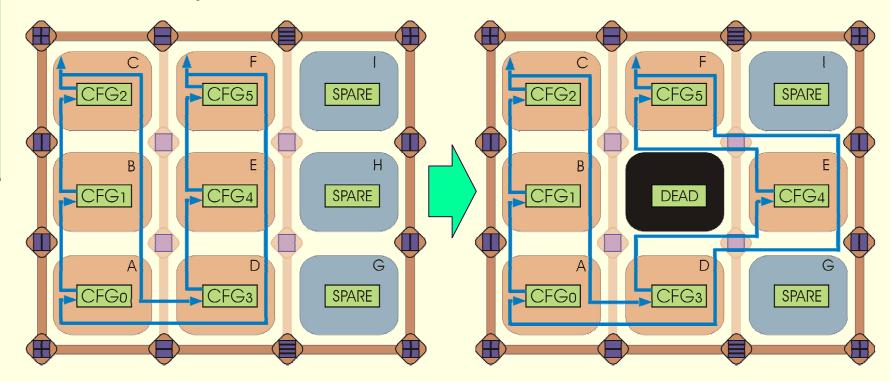
Memory molecules from within the same macro-molecule are all chained together

Data is shifted continuously cyclic-type memory

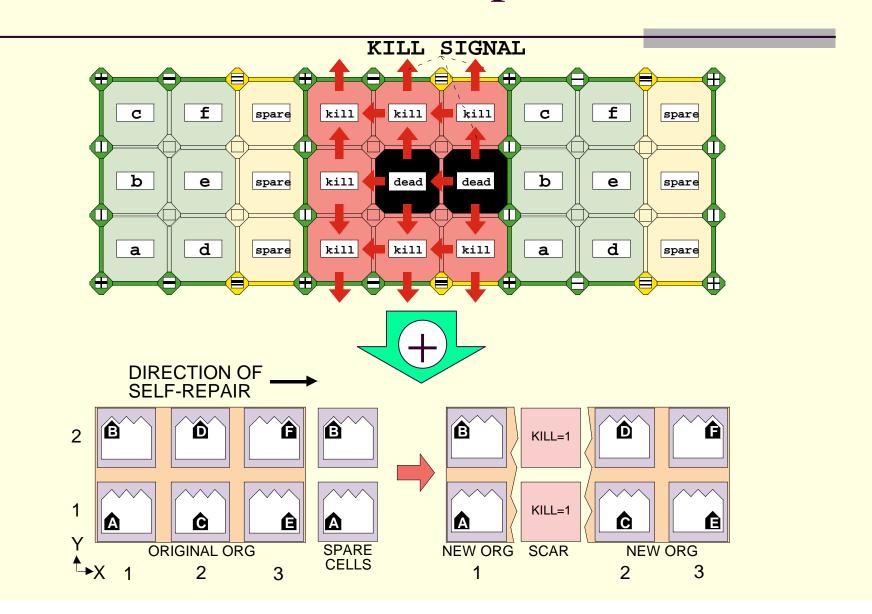
Molecular Self-Repair (Logic Mode)

A faulty molecule is replaced with a spare one, by transferring its functionality

The faulty molecule is then disabled, i.e. "dies"



Hierarchical Self-Repair



Molecular Self-Repair (Memory Mode)

Functionality transfer not possible in memory mode

Transferring genetic data from a faulty molecule to a spare one also transfers the fault(s), thus wasting valuable spare resources

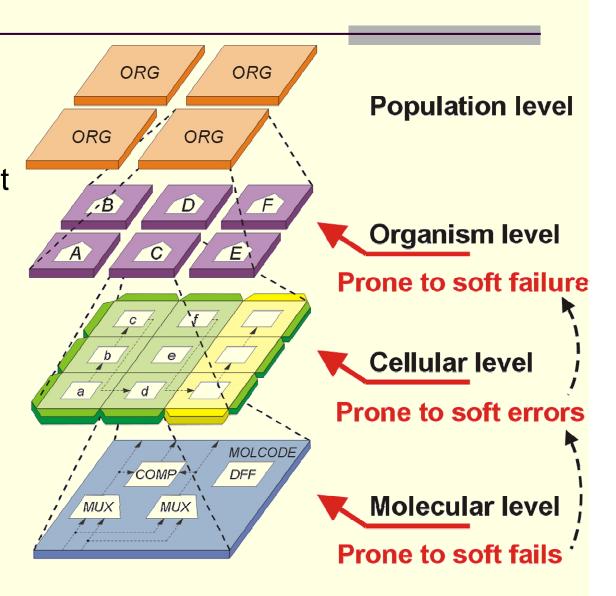


Existent self-repair mechanism therefore not able to ensure protection for macro-molecules

Memory Vulnerability

Memory affected by soft fails

Soft fails: transient errors induced by energized atomic particles that hit a semiconductor device



Origins of Soft Fails

Human expansion into space bound to aggressive radiation exposure

Experiments attempting to measure particle flux since 1980 (IBM)

Three categories of radiation

Primary cosmic rays: eventually may hit our planet; mostly protons (92%) and a Eparticles (6%)

Cascade particles, born form collisions when primary cosmic rays enter the earth's atmosphere

Terrestrial cosmic rays: energetic particles reaching the surface; mostly cascade-generated; only 1% due to primary cosmic rays

Soft Errors

"by far the most common type of chip failure is a soft error of a single cell on a chip"

Main cause for memory protection techniques: mitigation measures (physical level), parity codes, Error Checking and Correcting or ECC (data level)

Two issues concerning protective techniques for memory devices:

Error detection (low HW overhead)

Error correction (greater HW overhead but superior effectiveness)

Soft Error Rate

Chip type	Observed SER	Typical application
4Kb bipolar	1.340	Cache memory
288 Kb DRAM	126.000	Main memory
1Mb DRAM	3.000	Main memory
144Kb CMOS	210	Secondary cache
9Kb bipolar	998	I/O channels

Soft Error Rates for a variety of IBM memory chips show the effect of radiations over semiconductor devices

Embryonics

Robustness transfer from biology in Embryonics project hampered by memory vulnerability

Genetic program protected in biological entities; DNA capable of detecting and correcting a variety of faults

If Embryonics is to claim bio-inspired robustness, memory protection for most frequent upsetting scenario is a must

Reliability Analysis

Following scenarios possible:

Fault tolerance at the molecular level;

Advantage: isolate the faulty molecule, use the self-repair mechanism already in place;

Disadvantage: HW overhead

Fault tolerance at the macro-molecular level;

Advantage: ECC coding, lower HW overhead;

Disadvantage: no use for the existent self-repair

mechanisms

Memory Reliability w/o FT (1)

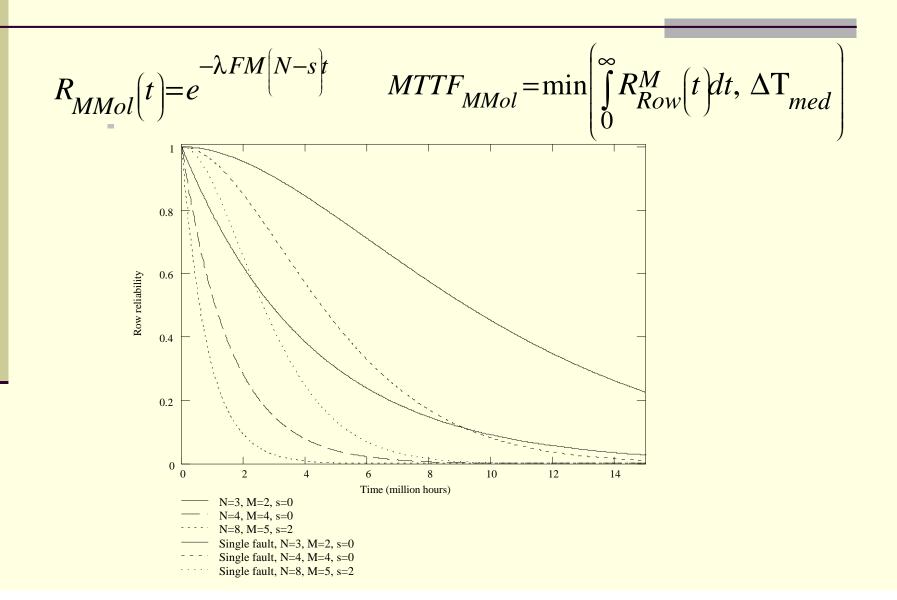
Macro-molecular dimensions: M lines, N columns, s spare columns

Each molecule stores F bits of genome data Failure rate for a storage flip-flop ?Õ

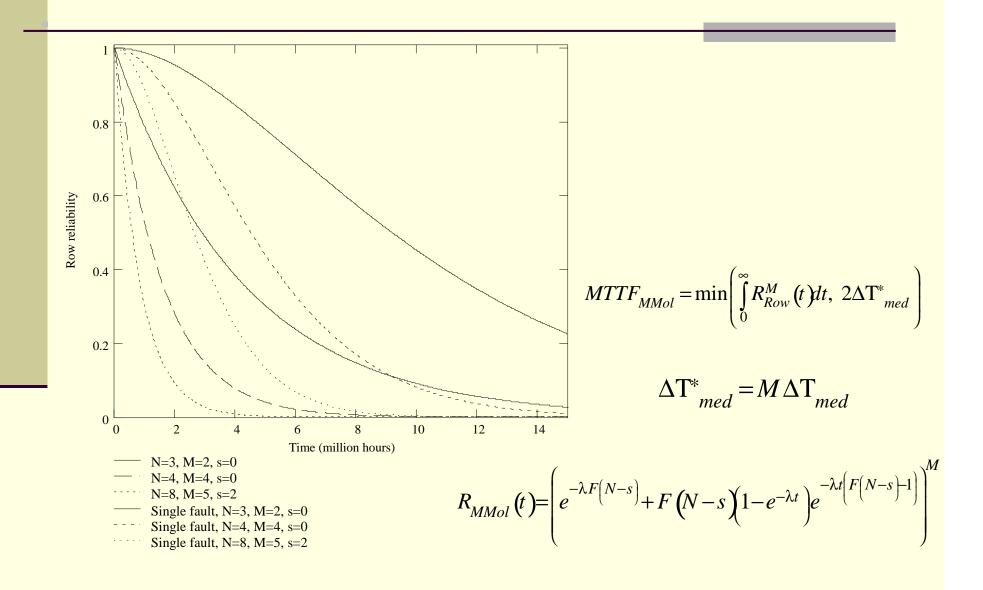
 ΔT_{med} mean period between two consequent upset events inside the macro-molecular area

R(t)=*Prob*{*unrecoverable error has not yet occurred*}

Memory Reliability w/o FT (2)



FT at the Molecular Level



The Failure Rate ?1

?æssentially an empirical parameter

Value determined by extensive measurements

Exposure to aggressive environments affects ? values

From a **constant parameter** (at sea-level and during standard environment conditions), ? becomes a **variable** (at high altitudes or in outer space, during non-standard conditions).

Fault Tolerant Memory Structures

Overall reliability increased by two fundamental techniques:

Fault prevention (aka fault intolerance) eliminates possible faults at the initial moment; already present in Embryonics

Fault tolerance allows valid computations through redundancy, even in the presence of faults; not present in Embryonics, subject of this paper

Fault Tolerance and Embryonics

Only the functional part of the molecule is currently fault tolerant

The addition of memory molecules not covered:

no error detection inside a memory molecule self-repairing mechanism overcome, preserving erroneous data; resource wasting while offering no data protection



ECC implementation necessary

Memory Datapath

$$V(L_{i,j}) = \begin{cases} (L_{i-1,j}L_{i,j}L_{i+1,j}), & \text{if } 1 < i < M, \ 1 < j < N \\ (L_{M,j-1}L_{1,j}L_{2,j}), & \text{if } i = 1, \ 1 < j \\ (L_{M,N}L_{1,1}L_{2,1}), & \text{if } i = j = 1 \end{cases}$$

$$MEM = \begin{pmatrix} L_{M,j} & L_{M,j}$$

$$M^* = \begin{bmatrix} 0 \\ F-1 & F \\ I_F \\ 0 \\ F+1 & F \end{bmatrix}$$

$$E(L_{ij})(k) = \begin{cases} 1, & \text{if bit k is erroneous} \\ 0, & \text{otherwise} \end{cases}$$

$$V(L_{i,j}) = (L_{6,3} \ L_{1,4} \ L_{2,4})$$

$$\mathbb{Z}_{i,j}^{0} = \left(V\left(L_{i,j}\right) \oplus E\left(L_{i,j}\right)\right) \times M^{*}$$

Example

Genome data words 4-bit-wide (4,7) code



Final structure for a FT macro-molecule:

Data macro-molecule

3 macro-molecules for check data

Additional error checking and correcting logic

Additional signals required:

Memory Hold – enables data shifting for a macro-molecule

INVert – enables data correction

Implementation

Protection for single errors (most frequent) Based on Hammingclass codes GENOME Multiple error detection possible

Control Signals

MHi	INV _{0 1 n-1 n}	Operation
0	11 11	Memory shift enabled
0	01 11	Memory shift with column 0 inverted
0	10 11	Memory shift with column 1 inverted
M	M	M
0	11 01	Memory shift with column n-1 inverted
0	11 10	Memory shift with column n inverted
1	xx xx	Memory shift disabled

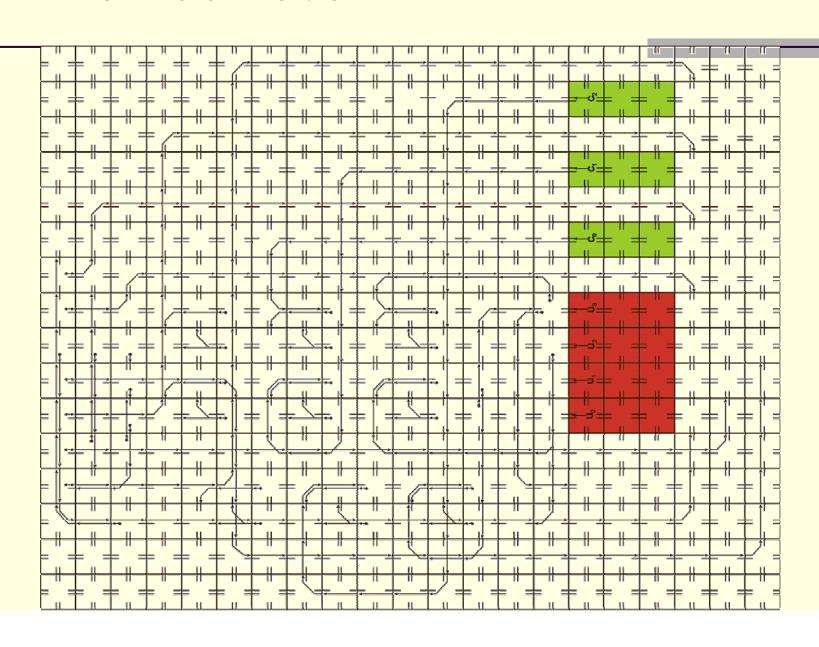
Final Design: Resource Levels

Two levels of configuration:

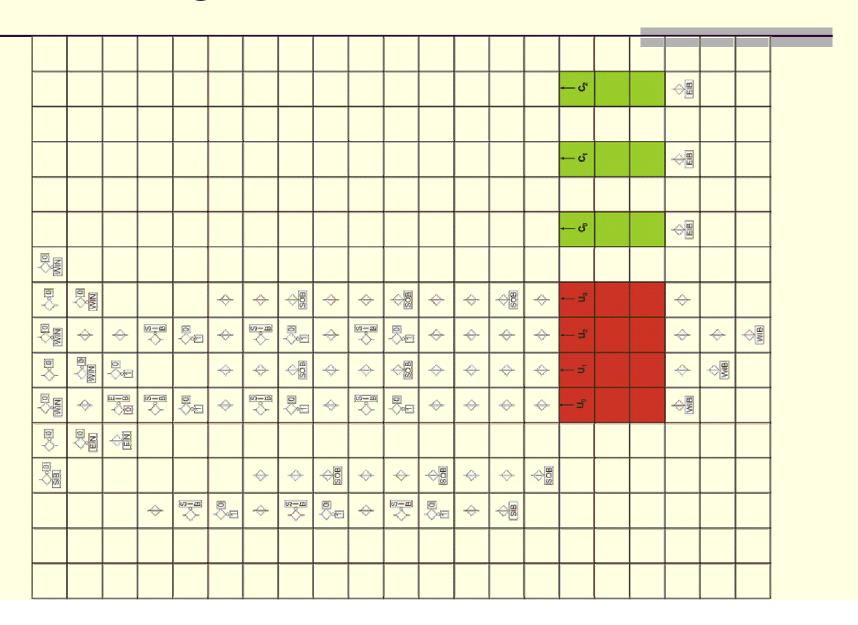
Bus level – contains routing information for all buses

Logic level – configures the Functional Unit and CREG for each molecule

The Bus Level



The Logic Level

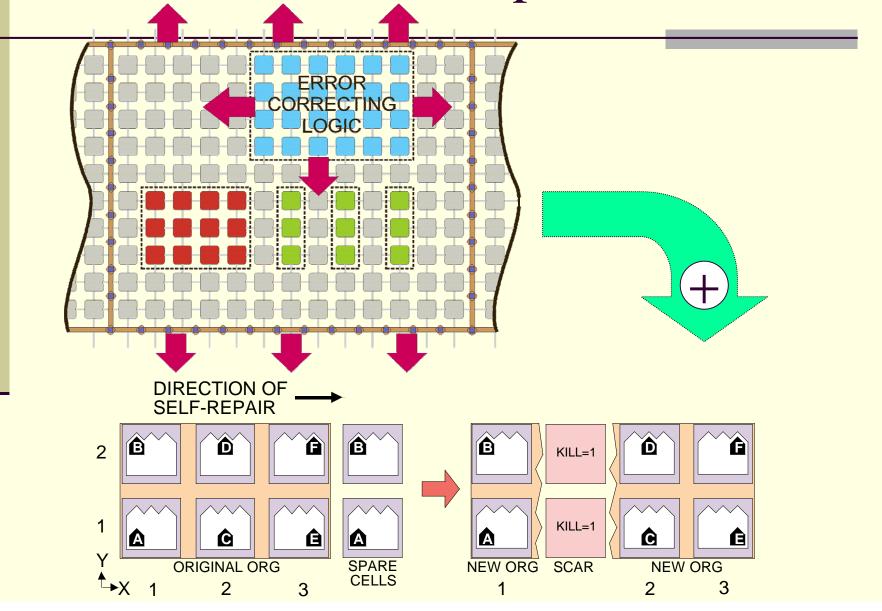


Self-Repairing Macro-Molecules

At the *molecular level*, single faults are detected and corrected by the Error Correcting Logic

If an occurring fault has been detected but cannot be corrected, the Error Correcting Logic triggers the KILL signal, which activates the self-repair at the *cellular level*

Hierarchical Self-Repair



Conclusions and Future Work

- ü Two-level self-repair now covering the memory structures
- ü Additional logic proportionally smaller when larger macro-molecules used
- ? Model for automatic fault tolerance assessment
- ? Design techniques with "Embryonics FPGA"
- ? ...

